

Search Notes

Application/Control No.

10/676,774

Examiner

Hau V. Phan

Applicant(s)/Patent under
Reexamination

STARKS, NEAL A.

Art Unit

3618

SEARCHED

Class	Subclass	Date	Examiner
280	288.4	3/1/2007	HP
	293		
	292		
	204		
	486		
224	419	3/1/2007	HP
	447		
	434		
	405		
403	109.1	1/3/2007	HP
	109.6		
	109.3		
	362		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR